

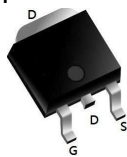
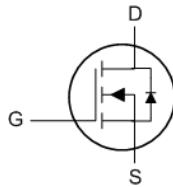


### Description

The 30N06 is the high cell density trench N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The 30N06 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

- 100% EAS Guaranteed
- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

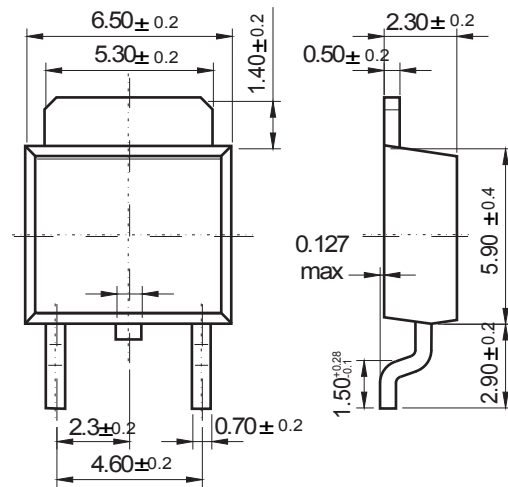


### Product Summary

BVDSS	RDSON	ID
60V	23mΩ	30 A

### TO-252

Unit: mm



### Absolute Maximum Ratings (T<sub>C</sub>=25°C unless otherwise specified)

Symbol	Parameter	Max.	Units
V <sub>DSS</sub>	Drain-Source Voltage	60	V
V <sub>GSS</sub>	Gate-Source Voltage	±30	V
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> = 25°C	30
		T <sub>C</sub> = 100°C	13
I <sub>DM</sub>	Pulsed Drain Current <sup>note1</sup>	100	A
EAS	Single Pulsed Avalanche Energy <sup>note2</sup>	39	mJ
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C	41.7
R <sub>θJC</sub>	Thermal Resistance, Junction to Case	50	°C/W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +175	°C

# 30N06

## Electrical Characteristics (T<sub>J</sub> = 25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	60	-	-	V
Gate-Body Leakage Current	I <sub>gss</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
Zero Gate Voltage Drain Current	T <sub>J</sub> =25°C	I <sub>DSS</sub> V <sub>DS</sub> = 60V, V <sub>GS</sub> = 0V	-	-	1	μA
	T <sub>J</sub> =100°C		-	-	100	
Gate-Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.7	2.5	V
Drain-Source on-Resistance <sup>4</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A	-	23	32	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 5A	-	31.5	40	
Forward Transconductance <sup>4</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 10A	-	15.5	-	S
<b>Dynamic Characteristics<sup>5</sup></b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V, f = 1MHz	-	1355	-	pF
Output Capacitance	C <sub>oss</sub>		-	60	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	49	-	
Gate Resistance	R <sub>G</sub>	f = 1MHz	-	1.2	-	Ω
<b>Switching Characteristics<sup>5</sup></b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 30V, I <sub>D</sub> = 10A	-	22	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	4.2	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	6.9	-	
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 30V, R <sub>G</sub> = 3Ω, I <sub>D</sub> = 10A	-	6.4	-	ns
Rise Time	t <sub>r</sub>		-	15.3	-	
Turn-off Delay Time	t <sub>d(off)</sub>		-	25	-	
Fall Time	t <sub>f</sub>		-	7.6	-	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 10A, dI <sub>F</sub> /dt = 100A/μs	-	26	-	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		-	45	-	nC
<b>Drain-Source Body Diode Characteristics</b>						
Diode Forward Voltage <sup>4</sup>	V <sub>SD</sub>	I <sub>S</sub> = 10A, V <sub>GS</sub> = 0V	-	-	1.2	V
Continuous Source Current	I <sub>S</sub>	T <sub>C</sub> = 25°C	-	-	30	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub> = 150°C
2. The EAS data shows Max. rating. The test condition is V<sub>DD</sub> = 25V, V<sub>GS</sub> = 10V, L = 0.4mH, I<sub>AS</sub> = 14A
3. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%.
5. This value is guaranteed by design hence it is not included in the production test.

## RATING AND CHARACTERISTIC CURVES (30N06)

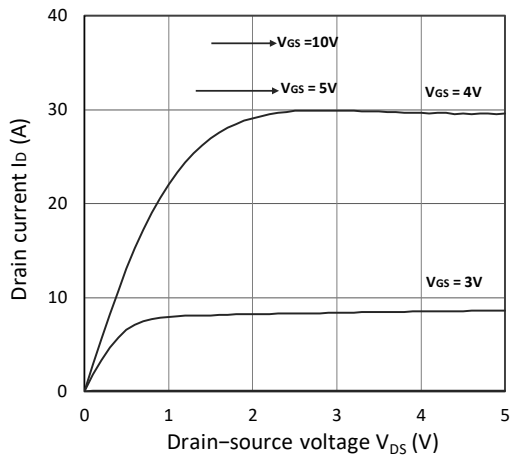


Figure 1. Output Characteristics

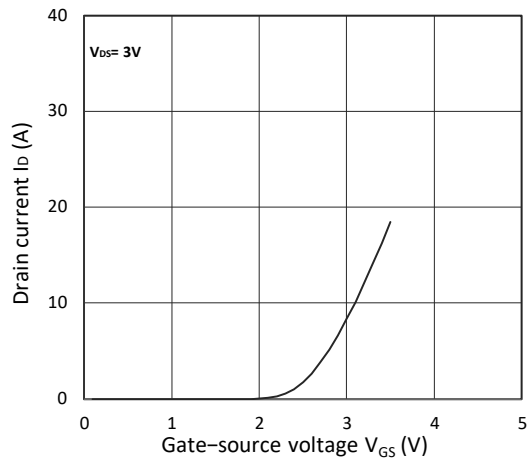


Figure 2. Transfer Characteristics

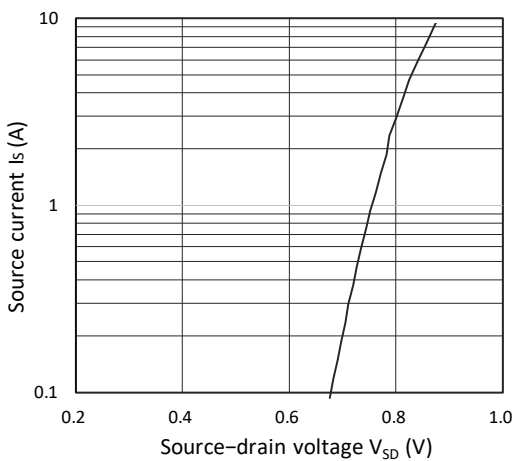


Figure 3. Forward Characteristics of Reverse

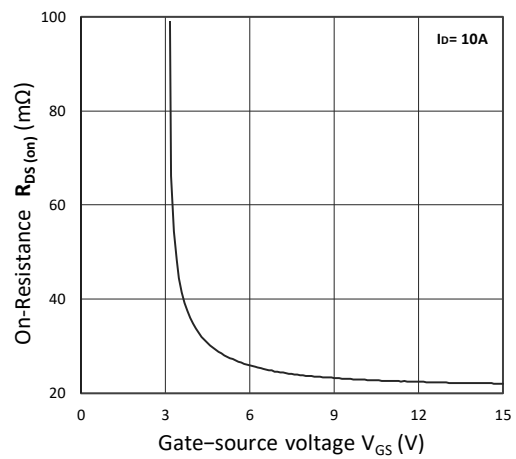


Figure 4.  $R_{DS(ON)}$  vs.  $V_{GS}$

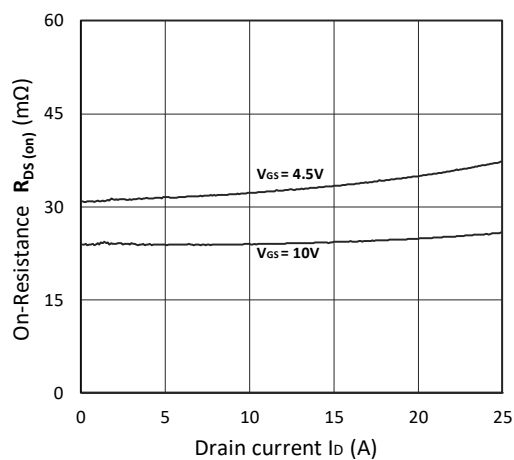


Figure 5.  $R_{DS(ON)}$  vs.  $I_D$

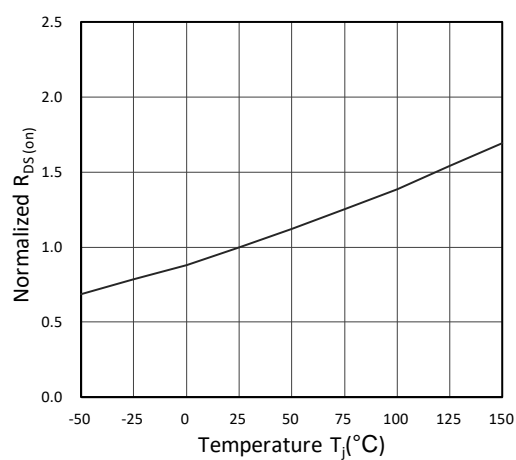


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature

## RATING AND CHARACTERISTIC CURVES (30N06)

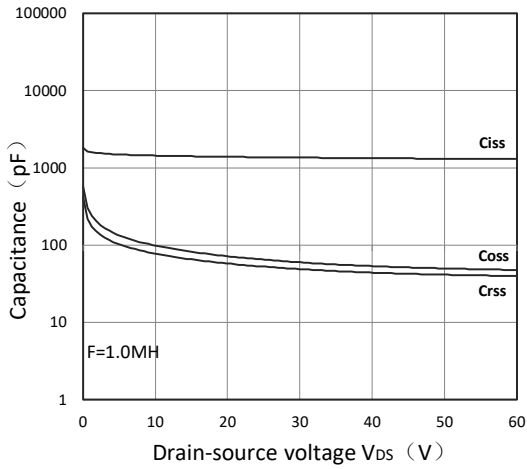


Figure 7. Capacitance Characteristics

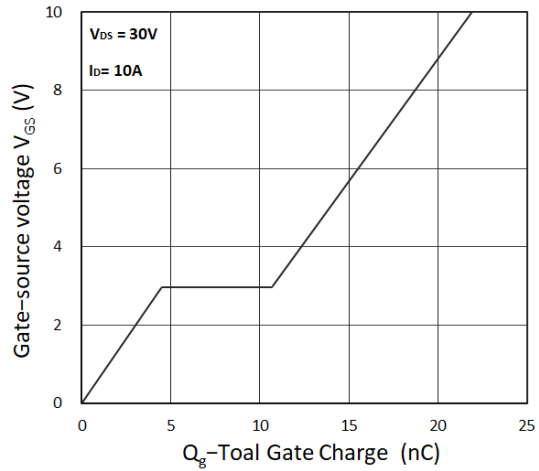


Figure 8. Gate Charge Characteristics

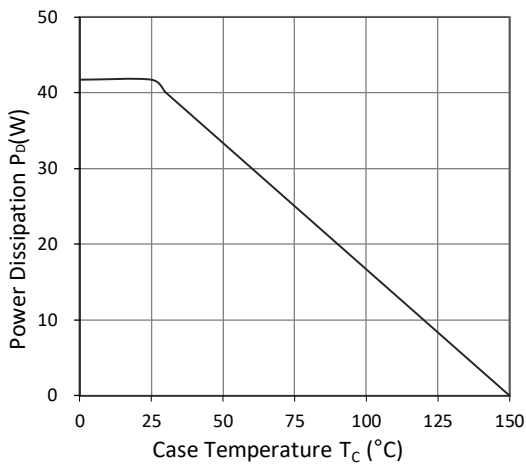


Figure 9. Power Dissipation

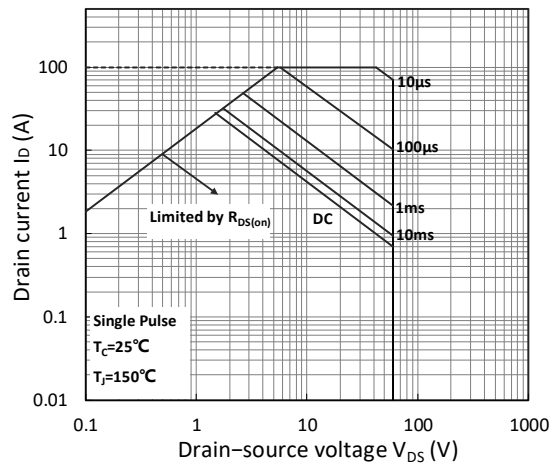


Figure 10. Safe Operating Area

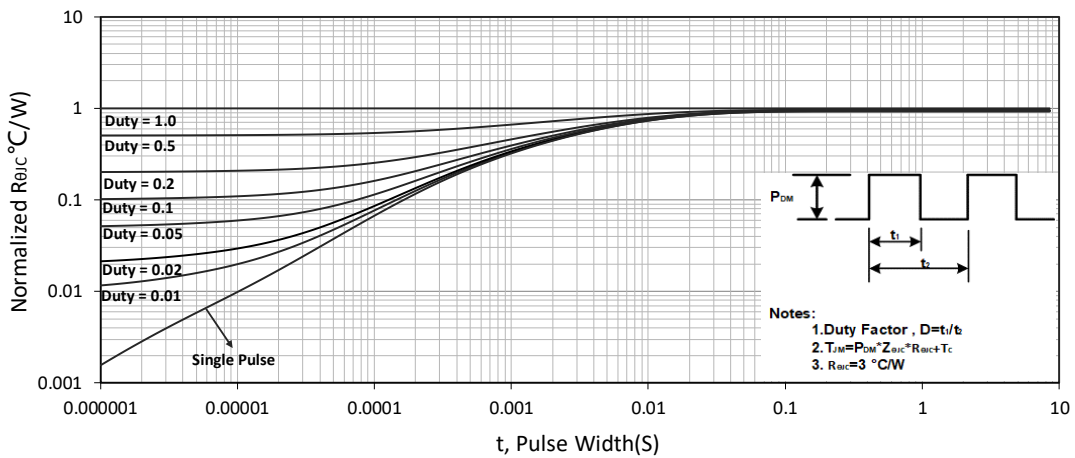


Figure 11. Normalized Maximum Transient Thermal Impedance